Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	8634	(data with (select selecting selection) with (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22
L15	1126	((sample specimen wafer die) with (matrix array) with (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L16	183	((pca (principal adj component adj analysis)) with (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L17	81	(model with maintenance with (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L18	537	((product sample specimen wafer die defect error fault) with (classing classifying classification categorizing categorize category categorization) with (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L19	66	l14 and l15	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L20	12	l14 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L21	15	l14 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L22	45	l14 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L23	30	l15 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L24	0	l15 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L25	6	l15 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:19
L26	0	l16 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L27	1	l16 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L28	2	l17 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:20
L29	1	l14 and l15 and l16	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22

L30	0	l14 and l15 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L31	1	l14 and l15 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L32	0	l14 and l15 and l16 and l17	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L33	0	l14 and l15 and l16 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L34	0	l14 and l15 and l17 and l18	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:21
L35	1454	(data near3 (select selecting selection) near3 (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:22
L36	167	((sample specimen wafer die) near3 (matrix array) near3 (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L37	48	((pca (principal adj component adj analysis)) near3 (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L38	11	(model near3 maintenance near3 (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:23
L39	125	((product sample specimen wafer die defect error fault) near3 (classing classifying classification categorizing categorize category categorization) near3 (module routine sub$routine))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:26
L40	1	l35 and l36	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L41	0	l35 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L42	0	l35 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L43	2	l35 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L44	0	l36 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L45	0	l36 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27
L46	0	l36 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:27

L47	0	137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L48	0	137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L49	2	138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:31
L50	0	135 and 136 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L51	0	135 and 136 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:28
L52	0	135 and 136 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L53	0	135 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L54	0	135 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L55	0	135 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L56	0	135 and 136 and 137 and 138	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L57	0	135 and 136 and 137 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:29
L58	0	135 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:30
L59	0	135 and 136 and 137 and 138 and 139	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:30
L60	352656	(industrial manufacturing plasma etch etching) near3 process	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L61	93	160 and 135	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L62	49	160 and 136	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L63	6	160 and 137	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32

L64	3	l60 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L65	36	l60 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:32
L66	0	l60 and l36 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L67	0	l60 and l36 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L68	0	l60 and l36 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L69	0	l60 and l35 and l36	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L70	0	l60 and l35 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L71	0	l60 and l35 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L72	0	l60 and l35 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L73	0	l60 and l37 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L74	0	l60 and l37 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:33
L75	2	l60 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L76	0	l60 and l35 and l36 and l37	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L77	0	l60 and l35 and l36 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L78	0	l60 and l35 and l36 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L79	0	l60 and l35 and l37 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L80	0	l60 and l35 and l37 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34

L81	0	l60 and l35 and l36 and l37 and l38	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L82	0	l60 and l35 and l36 and l37 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:34
L83	0	l60 and l35 and l37 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
L84	0	l60 and l35 and l36 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
L85	0	l60 and l35 and l36 and l37 and l38 and l39	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 11:35
S1	10	("5658423" "5864773" "6153115" "6192826" "6419846" "6442445" "6521080" "20020104832" "20020119668" "20030055523").pn.	US-PGPUB; USPAT	OR	OFF	2004/12/21 10:31
S2	2318	principal adj component adj analysis	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/30 06:50
S3	271	(principal adj component adj analysis) and ((industrial or plasma or manufacturing) adj process)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2004/12/21 10:33
S4	677	(principal adj component adj analysis) and ((identify identifying identification identifiable determine determining determination determinable identified determined detect detecting detection detectable) with (error fault flaw defect anomoly malfunction erroneous faulty flawed defective anomolous malfunctioning))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S5	157	S4 and ((plasma industrial manufacturing wafer etch etching) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:15
S6	104	S5 and (predict predicted prediction predictable predicting forecast forecasting forecasted)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:16
S7	2447	(principal adj component) and ((identify identifying identification identifiable determine determining determination determinable identified determined detect detecting detection detectable) with (error fault flaw defect anomoly malfunction erroneous faulty flawed defective anomolous malfunctioning))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:15

S8	369	S7 and ((plasma industrial manufacturing wafer etch etching) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:16
S9	195	S8 and (predict predicted prediction predictable predicting forecast forecasting forecasted)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:17
S10	162	S9 and (compute computing computation calculate or claculating calculation calculable computed calculated) and (category catagorizing catagorized sort sorted sorting correlate correlated correlating correlation collate collating collated collation)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:25
S11	102	S10 and (residue residual)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:26
S12	101	S11 and (single singular)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:28
S13	97	S12 and (matrix array matrices)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:34
S14	81	S13 and vector	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:41
S15	11	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:50
S16	59	("5658423").URPN.	USPAT	OR	OFF	2004/12/23 10:55
S17	9	("5121337" | "5288367" | "5479340" | "5552016" | "5658423" | "5862060" | "5885472" | "6060328" | "6153115").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:56
S18	11	("6238937").URPN.	USPAT	OR	OFF	2004/12/23 10:57
S19	9	("5121337" | "5288367" | "5479340" | "5658423" | "5862060" | "5885472" | "6060328" | "6153115" | "6238937").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:57
S20	7	("5121337" | "5288367" | "5479340" | "5658423" | "5862060" | "6238937" | "6419846").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:58
S21	1	("6564114").URPN.	USPAT	OR	OFF	2004/12/23 10:58
S22	9	("5121337" | "5288367" | "5479340" | "5658423" | "5862060" | "6153115" | "6238937" | "6368879" | "6419846").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 10:58
S23	0	("6582618").URPN.	USPAT	OR	OFF	2004/12/23 10:50
S24	0	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:51

S25	0	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN. and S13	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:51
S26	0	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN. and S12	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S27	0	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN. and S11	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S28	0	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN. and S10	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S29	1	("4888199" | "5014217" | "5040734" | "5114233" | "5121337" | "5172312" | "5288367" | "5308414" | "5347460" | "5442562" | "5467883").PN. and S9	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:52
S30	6	("5658423").URPN. and S14	USPAT	OR	ON	2004/12/23 10:55
S31	1	("5121337" | "5288367" | "5479340" | "5552016" | "5658423" | "5862060" | "5885472" | "6060328" | "6153115").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:56
S32	3	("6238937").URPN. and S14	USPAT	OR	ON	2004/12/23 10:57
S33	2	("5121337" | "5288367" | "5479340" | "5658423" | "5862060" | "5885472" | "6060328" | "6153115" | "6238937").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:57
S34	3	("5121337" | "5288367" | "5479340" | "5658423" | "5862060" | "6238937" | "6419846").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 10:59
S35	0	("6564114").URPN. and S14	USPAT	OR	ON	2004/12/23 10:58
S36	3	("5121337" | "5288367" | "5479340" | "5658423" | "5862060" | "6153115" | "6238937" | "6368879" | "6419846").PN. and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:03
S37	7	("5467883" "6675137" "6582618" "6564114" "6549864" "6419846" "6238937" "5658423").PN. and S14	USPAT	OR	ON	2004/12/23 11:12
S38	320	438/5.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:22
S39	558	700/90.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S40	448	700/95.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S41	467	700/108.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13

S42	236	700/109.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S43	319	700/110.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S44	448	700/117.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S45	1131	700/121.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:13
S46	499	702/117.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S47	211	702/118.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S48	104	702/121.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S49	839	702/182.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S50	676	702/183.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S51	372	702/185.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S52	516	702/189.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S53	58	702/196.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S54	218	438/8.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S55	251	438/9.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:14
S56	96	438/5.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23
S57	80	438/8.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23

S58	97	438/9.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:23
S59	28	700/90.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S60	75	700/95.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S61	155	700/108.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S62	90	700/109.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:24
S63	98	700/110.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S64	74	700/117.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S65	281	700/121.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S66	23	702/117.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S67	19	702/118.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S68	8	702/121.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S69	149	702/182.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25
S70	133	702/183.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:25

S71	71	702/185.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S72	59	702/189.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S73	5	702/196.ccls. and ((monitor monitoring monitored watch watched watching audit audited auditing review reviewed reviewing) near3 process)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:26
S74	4	S56 and S4	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S75	4	S57 and S4	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:27
S76	0	S56 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S77	1	S57 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S78	5	S58 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S79	0	S59 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S80	0	S60 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S81	1	S61 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S82	0	S62 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S83	1	S63 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:31
S84	1	S64 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:30
S85	3	S65 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S86	0	S66 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28

S87	0	S67 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:28
S88	0	S68 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S89	0	S69 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S90	1	S70 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:31
S91	0	S71 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S92	0	S72 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S93	0	S73 and S14	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/23 11:29
S94	14	("5130936" | "5133046" | "5148378" | "5237518" | "5267277" | "5465321" | "5548378" | "5629872" | "5642296" | "5661666" | "5680409" | "5715178" | "5726915" | "6219626").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/23 11:32
S95	4	("6415276").URPN.	USPAT	OR	OFF	2004/12/23 11:35
S96	10	("5467883" "6675137" "6582618" "6564114" "6549864" "6419846" "6238937" "5658423" "6415276" "20030109951").pn.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:47
S97	158	jahns.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S98	0	jahns-gary.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S99	0	zhang-y.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S100	0	palladino-a.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S101	69	palladino.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:48
S102	8231	zhang.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S103	0	zhang-yixin.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S104	0	palladino-anthony.in.	US-PGPUB; USPAT	OR	OFF	2004/12/23 11:49
S105	57	(jahns zhang palladino).in. and ((principal adj component adj analysis) pca)	US-PGPUB; USPAT	OR	ON	2004/12/29 09:50
S106	1	"5711843".pn.	USPAT	OR	OFF	2004/12/23 11:56

S107	92	((industrial or manufacturing or production or plasma) near3 process) and ((fault or flaw or defect or malfunction) near4 (detect$3 or determin$5 or discover$3)) and ((principal adj component adj analysis) pca)	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 09:56
S108	16697	((process procedure method) near3 (error fault flaw defect malfunction) near3 (detect detecting detection determine determining determination))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 14:28
S109	107	S108 and (pca (principal adj component adj analysis))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/29 14:27
S110	313	((industrial manufacturing plasma etching) near3 (process procedure method) near3 (error fault flaw defect malfunction) near3 (detect detecting detection determine determining determination))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 06:43
S111	30	(pca (principal adj component adj analysis)) and (((industr$3 manufactur$3 assembl$3 produc$4) near3 (process procedure)) with (defect$3 fault flaw error malfunction$3) with (detect$3 determin$5 locat$3 find$3))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 08:18
S112	5	("6521080" "6368975" "5864773" "5658423" "20030136511").pn.	US-PGPUB; USPAT	OR	ON	2004/12/30 07:09
S113	21	("5274572" | "5305221" | "5319580" | "5386373" | "5406502" | "5453156" | "5459668" | "5465321" | "5479340" | "5486995" | "5526293" | "5528510" | "5548528" | "5566092" | "5570300" | "5642296" | "5646870" | "5655110" | "5658423" | "5659467" | "5680409").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S114	28	("5864773").URPN.	USPAT	OR	OFF	2004/12/30 07:17
S115	6	("4312732" | "5653894" | "5711843" | "5885472" | "5966586" | "6017414").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S116	3	("6368975").URPN.	USPAT	OR	OFF	2004/12/30 07:18
S117	12	("4312732" | "5288367" | "5653894" | "5658423" | "5711843" | "5885472" | "5966586" | "6017414" | "6153115" | "6368975" | "6381008" | "6413867").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2004/12/30 07:18
S118	1	("6521080").URPN.	USPAT	OR	OFF	2004/12/30 07:19
S119	2	("5274572" | "5305221" | "5319580" | "5386373" | "5406502" | "5453156" | "5459668" | "5465321" | "5479340" | "5486995" | "5526293" | "5528510" | "5548528" | "5566092" | "5570300" | "5642296" | "5646870" | "5655110" | "5658423" | "5659467" | "5680409").PN. and S111	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 07:13

S120	2	("5864773").URPN. and S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 07:15
S121	0	("4312732" | "5653894" | "5711843" | "5885472" | "5966586" | "6017414").PN. and S111	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 07:12
S122	1	("6368975").URPN. and S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 07:15
S123	3	("4312732" | "5288367" | "5653894" | "5658423" | "5711843" | "5885472" | "5966586" | "6017414" | "6153115" | "6368975" | "6381008" | "6413867").PN. and S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 07:16
S124	0	("6521080").URPN. and S111	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/30 07:13
S133	8	"356"/$.ccls. and (pca (principal adj component adj analysis)) and (process with ((error flaw defect fault malfunction) near5 (detect detecting detection determine determining determination determined detected)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 08:34
S134	27	"438"/$.ccls. and (pca (principal adj component adj analysis)) and (process with ((error flaw defect fault malfunction) near5 (detect detecting detection determine determining determination determined detected)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 08:36
S135	31	"700"/$.ccls. and (pca (principal adj component adj analysis)) and (process with ((error flaw defect fault malfunction) near5 (detect detecting detection determine determining determination determined detected)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 08:40
S136	27	"702"/$.ccls. and (pca (principal adj component adj analysis)) and (process with ((error flaw defect fault malfunction) near5 (detect detecting detection determine determining determination determined detected)))	US-PGPUB; USPAT; USOCR	OR	ON	2004/12/30 10:24

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1 **Recent experiences in the industrial exploitation of principal comp based fault detection methods**
Lennox, B.;
Computer Aided Control System Design, 2002. Proceedings. 2002 IEEE International Symposium on , 18-20 Sept. 2002
Pages:x

[Abstract] [PDF Full-Text (987 KB)] **IEEE CNF**

---

2 **A new fault detection and diagnosis method based on principal component analysis in multivariate continuous processes**
Yang Yinghua; Lu Ningyun; Wang Fuli; Ma Liling;
Intelligent Control and Automation, 2002. Proceedings of the 4th World Congr on , Volume: 4 , 10-14 June 2002
Pages:3156 - 3160 vol.4

[Abstract] [PDF Full-Text (499 KB)] **IEEE CNF**

---

3 **Multivariate statistics and neural networks in process fault detecti**
Martin, E.B.; Morris, A.J.;
Qualitative and Quantitative Modelling Methods for Fault Diagnosis, IEE Colloq on , 24 Apr 1995
Pages:7/1 - 7/8

[Abstract] [PDF Full-Text (496 KB)] **IEE CNF**

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---

1 **Spatial characterization of wafer state using principal component analysis of optical emission spectra in plasma etch**
White, D.A.; Boning, D.; Butler, S.W.; Barna, G.G.;
Semiconductor Manufacturing, IEEE Transactions on , Volume: 10 , Issue: 1 , 1997
Pages:52 - 61

[Abstract] [PDF Full-Text (664 KB)] **IEEE JNL**

---

2 **Process performance monitoring using multivariate statistical pr ce control**
Martin, E.B.; Morris, A.J.; Zhang, J.;
Control Theory and Applications, IEE Proceedings- , Volume: 143 , Issue: 2 , I 1996
Pages:132 - 144

[Abstract] [PDF Full-Text (1316 KB)] **IEE JNL**

---

3 **Using PCA to model shape for process control**
Crida, R.C.; Stoddart, A.J.; Illingworth, J.;
3-D Digital Imaging and Modeling, 1997. Proceedings., International Conferen Recent Advances in , 12-15 May 1997
Pages:318 - 325

[Abstract] [PDF Full-Text (904 KB)] **IEEE CNF**

---

4 **Modeling and filtering f ptical emission spectrosc py data f r plas etching systems**
Rangan, S.; Spanos, C.; Poolla, K.;
Semiconductor Manufacturing Conference Proceedings, 1997 IEEE Internation

Symposium on , 6-8 Oct. 1997
Pages:B41 - B44

[Abstract] [PDF Full-Text (380 KB)] IEEE CNF

---

5 **Modeling and filtering of optical emission spectroscopy. Data for pla etching systems**
Rangan, S.; Spanos, C.; Poolla, K.;
American Control Conference, 1997. Proceedings of the 1997 , Volume: 1 , 4-June 1997
Pages:627 - 628 vol.1

[Abstract] [PDF Full-Text (180 KB)] IEEE CNF

---

6 **Recent experiences in the industrial exploitation of principal comp i based fault detection methods**
Lennox, B.;
Computer Aided Control System Design, 2002. Proceedings. 2002 IEEE International Symposium on , 18-20 Sept. 2002
Pages:x

[Abstract] [PDF Full-Text (987 KB)] IEEE CNF

---

7 **A new fault detection and diagnosis method based on principal component analysis in multivariate continuous processes**
Yang Yinghua; Lu Ningyun; Wang Fuli; Ma Liling;
Intelligent Control and Automation, 2002. Proceedings of the 4th World Congr on , Volume: 4 , 10-14 June 2002
Pages:3156 - 3160 vol.4

[Abstract] [PDF Full-Text (499 KB)] IEEE CNF

---

8 **Neural network modeling of reactive ion etching using principal component analysis of optical emission spectroscopy data**
Hong, S.J.; May, G.S.;
Advanced Semiconductor Manufacturing 2002 IEEE/SEMI Conference and Workshop , 30 April-2 May 2002
Pages:415 - 420

[Abstract] [PDF Full-Text (587 KB)] IEEE CNF

---

9 **Principal component analysis for errors-in-variables subspace identification**
Jin Wang; Qin, S.J.;
Decision and Control, 2001. Proceedings of the 40th IEEE Conference on , Vol 4 , 4-7 Dec. 2001
Pages:3936 - 3941 vol.4

[Abstract] [PDF Full-Text (247 KB)] IEEE CNF

---

10 **An approach for relating m del parameter variabilities t process fluctuati ns**
Power, J.A.; Mathewson, A.; Lane, W.A.;

Microelectronic Test Structures, 1993. ICMTS 1993. Proceedings of the 1993 International Conference on , 22-25 March 1993
Pages:63 - 68

[Abstract] [PDF Full-Text (440 KB)] **IEEE CNF**

---

11 **A statistical perspective of neural networks for process modeling a control**
Qin, S.J.;
Intelligent Control, 1993., Proceedings of the 1993 IEEE International Sympos on , 25-27 Aug. 1993
Pages:599 - 604

[Abstract] [PDF Full-Text (472 KB)] **IEEE CNF**

---

12 **Statistical approaches to industrial process plant modelling**
Hartnett, M.; Irwin, G.W.;
Multidimensional Systems: Problems and Solutions (Ref. No. 1998/225), IEE Colloquium on , 14 Jan. 1998
Pages:7/1 - 7/8

[Abstract] [PDF Full-Text (528 KB)] **IEE CNF**

---

13 **Fault diagnosis in industrial process manufacturing using MSPC**
Weighell, M.; Martin, E.B.; Morris, A.J.;
Fault Diagnosis in Process Systems (Digest No: 1997/174), IEE Colloquium or April 1997
Pages:4/1 - 4/3

[Abstract] [PDF Full-Text (252 KB)] **IEE CNF**

---

14 **Statistical worst-case simulation for CMOS technology**
Welten, M.; Clancy, R.; Power, J.A.; Mason, B.; Stribley, P.; Mathewson, A.;
Improving the Efficiency of IC Manufacturing Technology, IEE Colloquium on , Apr 1995
Pages:4/1 - 4/3

[Abstract] [PDF Full-Text (220 KB)] **IEE CNF**

---

15 **Multivariate statistics and neural networks in process fault detectic**
Martin, E.B.; Morris, A.J.;
Qualitative and Quantitative Modelling Methods for Fault Diagnosis, IEE Colloq on , 24 Apr 1995
Pages:7/1 - 7/8

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---

1 **Fusion of fuzzy/neuro/evolutionary computing for knowledge acquisition**
Furuhashi, T.;
Proceedings of the IEEE , Volume: 89 , Issue: 9 , Sept. 2001
Pages:1266 - 1274

[Abstract] [PDF Full-Text (160 KB)] IEEE JNL

---

2 **Applications of principal component analysis and factor analysis in t identification of multivariable systems**
Priestley, M.; Rao, T.; Tong, H.;
Automatic Control, IEEE Transactions on , Volume: 19 , Issue: 6 , Dec 1974
Pages:730 - 734

[Abstract] [PDF Full-Text (552 KB)] IEEE JNL

---

3 **Principal component analysis in linear systems: Controllability, observability, and model reduction**
Moore, B.;
Automatic Control, IEEE Transactions on , Volume: 26 , Issue: 1 , Feb 1981
Pages:17 - 32

[Abstract] [PDF Full-Text (1296 KB)] IEEE JNL

---

4 **On the structure of balanced and other principal representations f systems**
Fernando, K.; Nicholson, H.;
Automatic Control, IEEE Transactions on , Volume: 28 , Issue: 2 , Feb 1983
Pages:228 - 231

[Abstract] [PDF Full-Text (416 KB)] IEEE JNL

---

5 **Principal c mp nent analysis f flexible systems--Open-l p case**
Jonckheere, E.;
Automatic Control, IEEE Transactions on , Volume: 29 , Issue: 12 , Dec 1984
Pages:1095 - 1097

[Abstract] [PDF Full-Text (352 KB)] IEEE JNL

---

6 **Coffee analysis with an electronic nose**
Pardo, M.; Sberveglieri, G.;
Instrumentation and Measurement, IEEE Transactions on , Volume: 51 , Issue 6 , Dec. 2002
Pages:1334 - 1339

[Abstract] [PDF Full-Text (376 KB)] IEEE JNL

---

7 **A study of the motion and deformation of the heart due to respiratio**
McLeish, K.; Hill, D.L.G.; Atkinson, D.; Blackall, J.M.; Razavi, R.;
Medical Imaging, IEEE Transactions on , Volume: 21 , Issue: 9 , Sept. 2002
Pages:1142 - 1150

[Abstract] [PDF Full-Text (706 KB)] IEEE JNL

---

8 **Real-time furnace modeling and diagnostics**
Jiangxin Wang; Spanos, C.J.;
Semiconductor Manufacturing, IEEE Transactions on , Volume: 15 , Issue: 4 , 2002
Pages:393 - 403

[Abstract] [PDF Full-Text (587 KB)] IEEE JNL

---

9 **3-D underwater object recognition**
Boulinguez, D.; Quinquis, A.;
Oceanic Engineering, IEEE Journal of , Volume: 27 , Issue: 4 , Oct. 2002
Pages:814 - 829

[Abstract] [PDF Full-Text (884 KB)] IEEE JNL

---

10 **Analytic PCA construction for theoretical analysis of lighting variab in images of a Lambertian object**
Ramamoorthi, R.;
Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 24 , Issue: 10 , Oct. 2002
Pages:1322 - 1333

[Abstract] [PDF Full-Text (564 KB)] IEEE JNL

---

11 **Face recogniti n by independent c mponent analysis**
Bartlett, M.S.; Movellan, J.R.; Sejnowski, T.J.;
Neural Networks, IEEE Transactions on , Volume: 13 , Issue: 6 , Nov. 2002
Pages:1450 - 1464

[Abstract] [PDF Full-Text (1405 KB)] IEEE JNL

12 **Applicati n of time-frequency principal c mp nent analysis t text-independent speaker identificati n**
Magrin-Chagnolleau, I.; Durou, G.; Bimbot, F.;
Speech and Audio Processing, IEEE Transactions on , Volume: 10 , Issue: 6 , :
2002
Pages:371 - 378

[Abstract] [PDF Full-Text (295 KB)] IEEE JNL

13 **Medical diagnosis with the gradient microarray of the KAMINA**
Koronczi, I.; Ziegler, K.; Kruger, U.; Goschnick, J.;
Sensors Journal, IEEE , Volume: 2 , Issue: 3 , June 2002
Pages:254 - 259

[Abstract] [PDF Full-Text (266 KB)] IEEE JNL

14 **Classification of bacteria responsible for ENT and eye infections usi the Cyranose system**
Boilot, P.; Hines, E.L.; Gardner, J.W.; Pitt, R.; John, S.; Mitchell, J.; Morgan, l
Sensors Journal, IEEE , Volume: 2 , Issue: 3 , June 2002
Pages:247 - 253

[Abstract] [PDF Full-Text (269 KB)] IEEE JNL

15 **A portable electronic nose based on embedded PC technology and GNU/Linux: hardware, software and applications**
Perera, A.; Sundic, T.; Pardo, A.; Gutierrez-Osuna, R.; Marco, S.;
Sensors Journal, IEEE , Volume: 2 , Issue: 3 , June 2002
Pages:235 - 246

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1 **Study on blind separation of underwater acoustic signals**
Zhang Xinhua; Zhang Anqing; Fang Jianping; Yang Shaoqing;
Signal Processing Proceedings, 2000. WCCC-ICSP 2000. 5th International Conference on , Volume: 3 , 21-25 Aug. 2000
Pages:1802 - 1805 vol.3

[Abstract] [PDF Full-Text (196 KB)] **IEEE CNF**

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2 **A kernel based nonlinear subspace projection method for reducti n hyperspectral image dimensionality**
Yanfeng Gu; Ye Zhang; Junping Zhang;
Image Processing. 2002. Proceedings. 2002 International Conference on , Vol 2 , 22-25 Sept. 2002
Pages:II-357 - II-360 vol.2

[Abstract] [PDF Full-Text (406 KB)] **IEEE CNF**

---

3 **A developing sensory mapping for robots**
Zhang, N.; Weng, J.; Zhang, Z.;
Development and Learning, 2002. Proceedings. The 2nd International Confere on , 12-15 June 2002
Pages:13 - 20

[Abstract] [PDF Full-Text (399 KB)] **IEEE CNF**

---

4 **Adaptive subspace decompositi n f r hyperspectral data dimensi n reduction**
Ye Zhang; Desai, M.D.; Junping Zhang; Ming Jin;
Image Processing, 1999. ICIP 99. Proceedings. 1999 International Conference on , Volume: 2 , 24-28 Oct. 1999

Pages:326 - 329 vol.2

[Abstract] [PDF Full-Text (376 KB)] IEEE CNF

---

5 **Aut matic image rientati n detection**
Vailaya, A.; Zhang, H.; Changjiang Yang; Feng-I Liu; Jain, A.K.;
Image Processing, IEEE Transactions on , Volume: 11 , Issue: 7 , July 2002
Pages:746 - 755

[Abstract] [PDF Full-Text (388 KB)] IEEE JNL

---

6 **Adaptive RLS algorithm for blind source separation using a natural gradient**
Xiao-Long Zhu; Xian-Da Zhang;
Signal Processing Letters, IEEE , Volume: 9 , Issue: 12 , Dec. 2002
Pages:432 - 435

[Abstract] [PDF Full-Text (288 KB)] IEEE JNL

---

7 **A class of learning algorithms for principal component analysis and minor component analysis**
Qingfu Zhang; Yiu Wing Leung;
Neural Networks, IEEE Transactions on , Volume: 11 , Issue: 1 , Jan. 2000
Pages:200 - 204

[Abstract] [PDF Full-Text (144 KB)] IEEE JNL

---

8 **A class of learning algorithms for principal component analysis and minor component analysis**
Zhang, Q.; Yiu-Wung Leung;
Neural Networks, IEEE Transactions on , Volume: 11 , Issue: 2 , March 2000
Pages:529 - 533

[Abstract] [PDF Full-Text (144 KB)] IEEE JNL

---

9 **Handwritten digit recognition by adaptive-subspace self-organizing (ASSOM)**
Bailing Zhang; Minyue Fu; Hong Yan; Jabri, M.A.;
Neural Networks, IEEE Transactions on , Volume: 10 , Issue: 4 , July 1999
Pages:939 - 945

[Abstract] [PDF Full-Text (248 KB)] IEEE JNL

---

10 **Dynamical system for computing the eigenvectors associated with largest eigenvalue of a positive definite matrix**
Bingfu Zhang; Zheng Bao;
Neural Networks, IEEE Transactions on , Volume: 6 , Issue: 3 , May 1995
Pages:790 - 791

[Abstract] [PDF Full-Text (160 KB)] IEEE JNL

---

11 **Energy function for the ne-unit Oja algorithm**
Qingfu Zhang; Yiu-Wing Leung;

Neural Networks, IEEE Transactions on , Volume: 6 , Issue: 5 , Sept. 1995
Pages:1291 - 1293

[Abstract] [PDF Full-Text (264 KB)] **IEEE JNL**

---

12 **MMP-PCA face recognition method**
Guangda Su; Cuiping Zhang; Rong Ding; Cheng Du;
Electronics Letters , Volume: 38 , Issue: 25 , 5 Dec. 2002
Pages:1654 - 1656

[Abstract] [PDF Full-Text (436 KB)] **IEE JNL**

---

13 **Process performance monitoring using multivariate statistical pr c control**
Martin, E.B.; Morris, A.J.; Zhang, J.;
Control Theory and Applications, IEE Proceedings- , Volume: 143 , Issue: 2 , I 1996
Pages:132 - 144

[Abstract] [PDF Full-Text (1316 KB)] **IEE JNL**

---

14 **Population optimization algorithm based on ICA**
Qingfu Zhang; Allinson, N.M.; Hujun Yin;
Combinations of Evolutionary Computation and Neural Networks, 2000 IEEE Symposium on , 11-13 May 2000
Pages:33 - 36

[Abstract] [PDF Full-Text (252 KB)] **IEEE CNF**

---

15 **On the roles of PCA and ICA in data fusion**
Chen, C.H.; Xiaohui Zhang;
Geoscience and Remote Sensing Symposium, 2000. Proceedings. IGARSS 20C IEEE 2000 International , Volume: 6 , 24-28 July 2000
Pages:2620 - 2622 vol.6

[Abstract] [PDF Full-Text (268 KB)] **IEEE CNF**

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